

pcim

ASIA

电能驱动新未来

28 – 30 August 2024

Hall 11, Shenzhen World Exhibition &
Convention Center, Shenzhen, China



KU LEUVEN



Energy
Ville



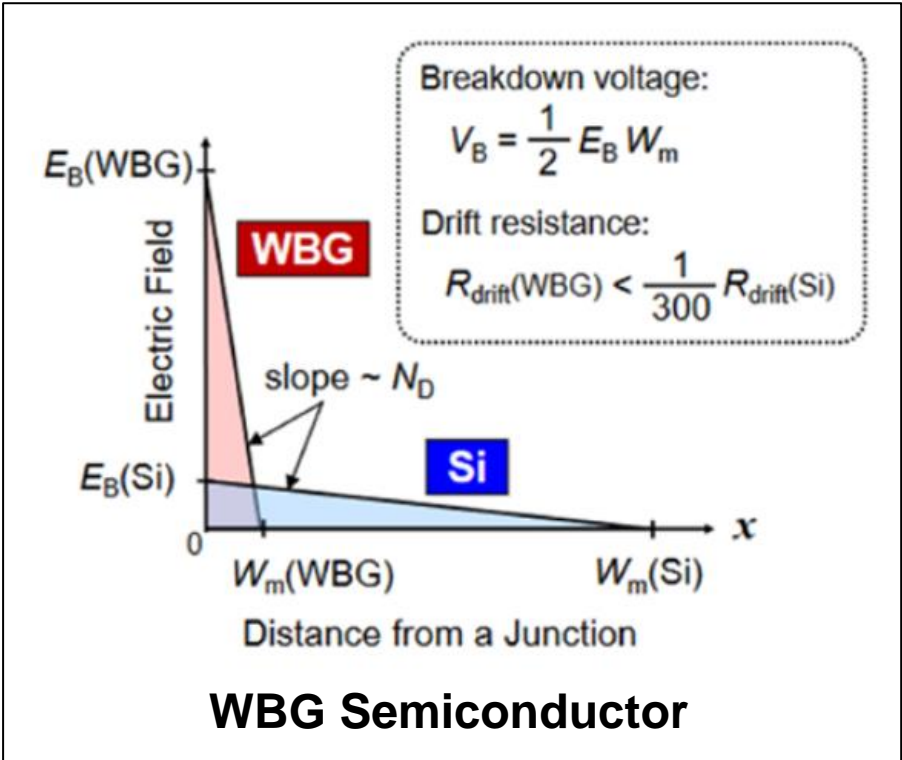
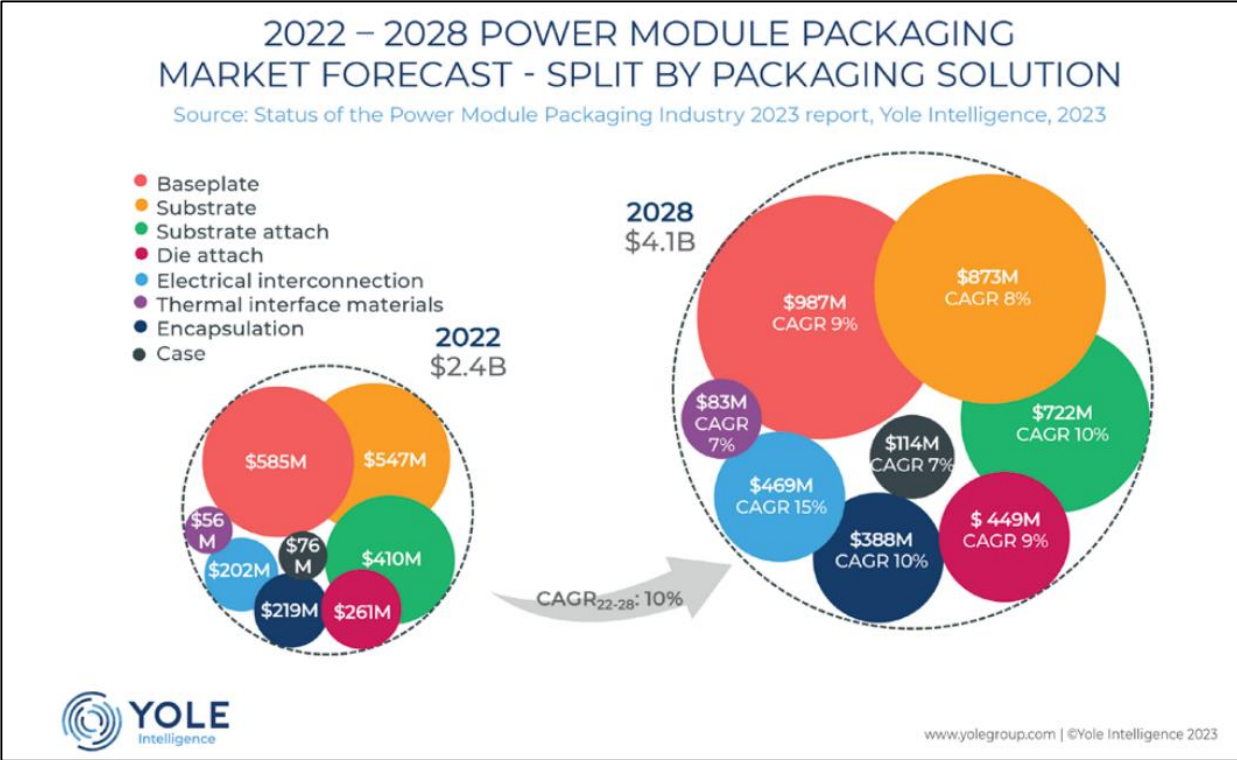
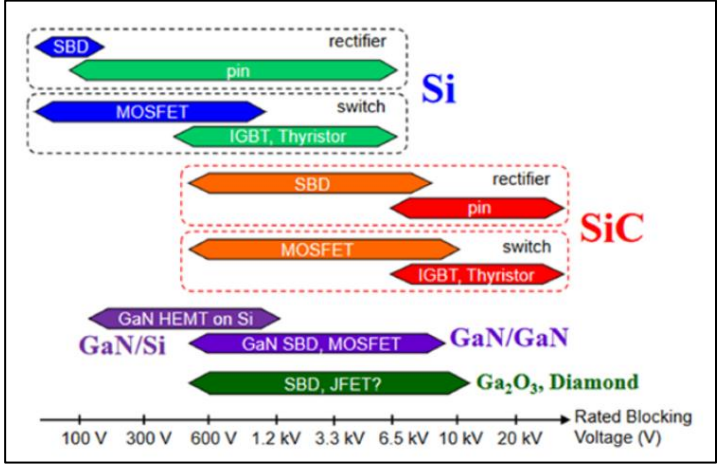
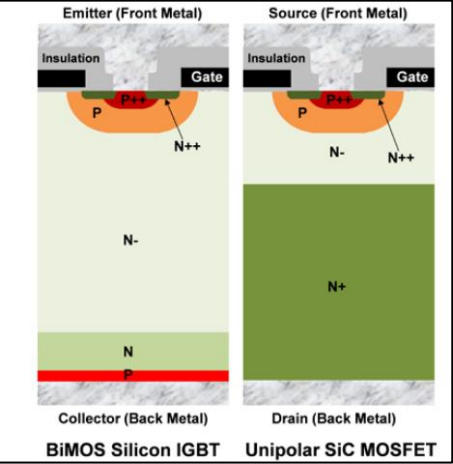
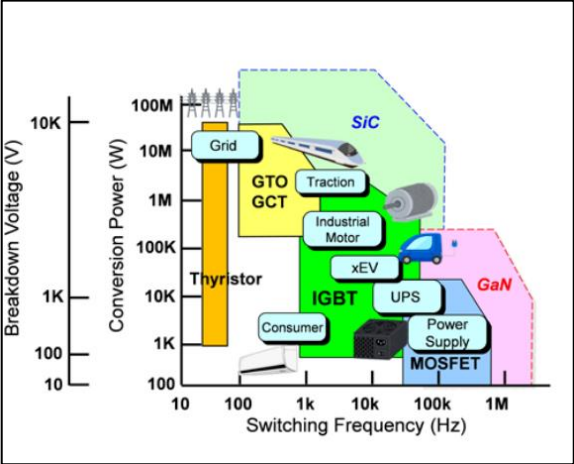
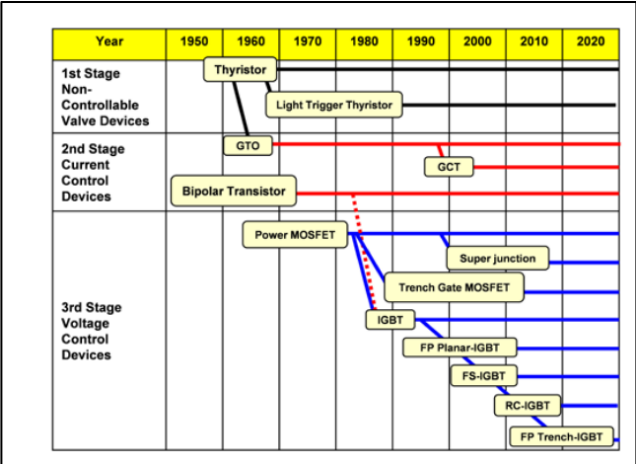
PCIM Conference Record

Wenjie Xu

09/2024



THE HONG KONG
POLYTECHNIC UNIVERSITY
香港理工大學



Power Brain – AI tool: Design automation for power converters

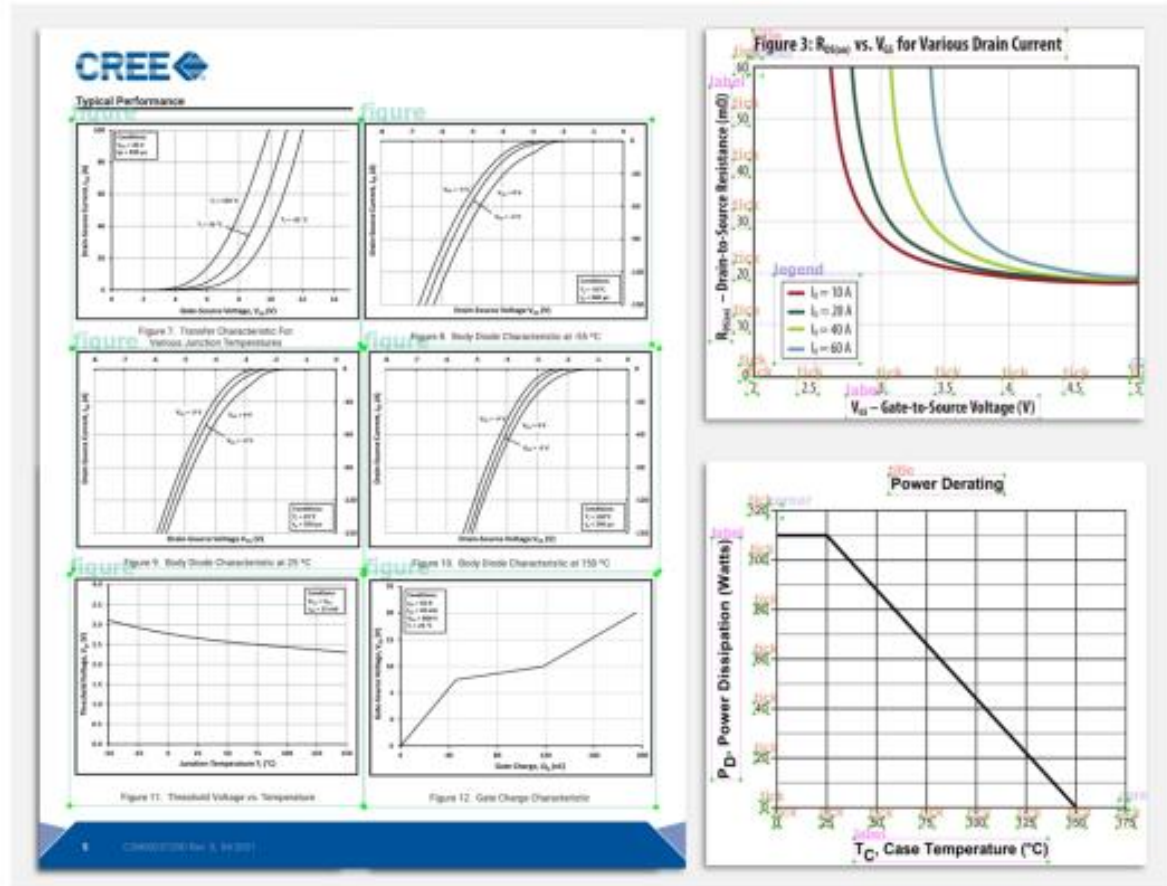


Fig. 2: Examples of the annoated PDF page and figures for object detection algorithm.

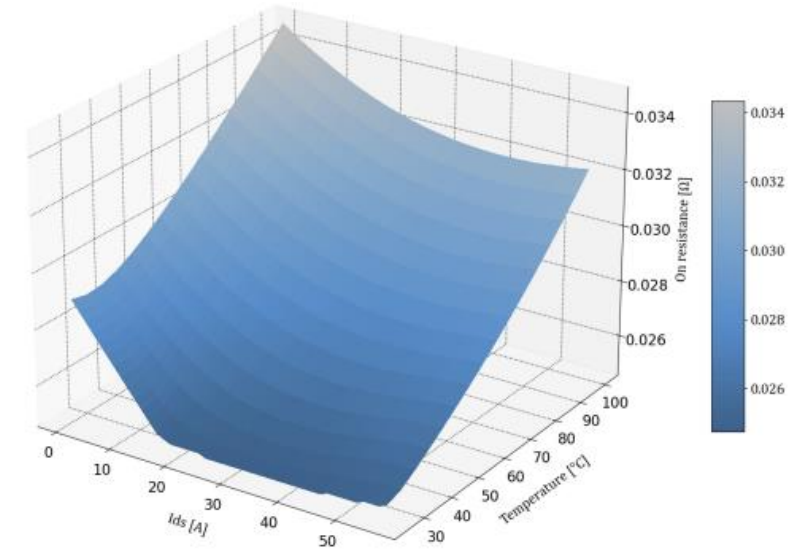


Fig. 7: An interpolation map of on-resistance.

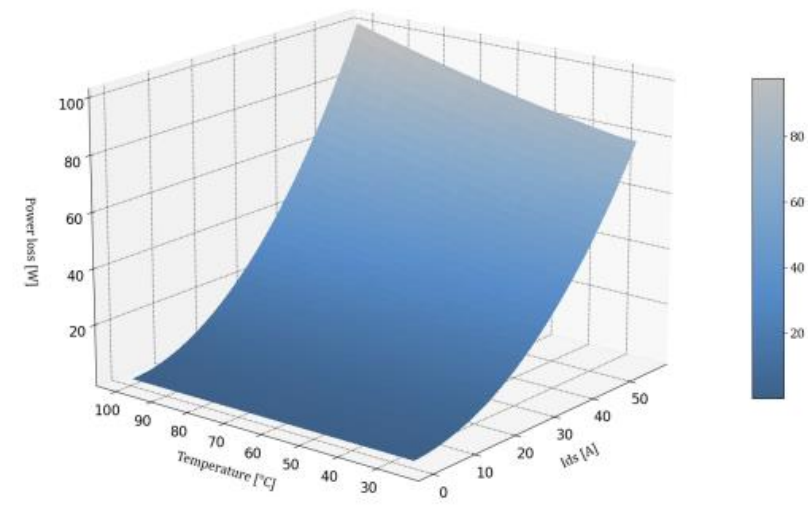


Fig. 8: An look-up table on conduction losses.

Magnetically Controlled Transformer With Variable Turns Ratio and Low Series Inductance: Analysis and Implementation Toward Its Application in SMPS

Camilo Suarez Buitrago ^{ID}, Diego Bernal Cobaleda ^{ID}, *Student Member, IEEE*,
and Wilmar Martinez ^{ID}, *Senior Member, IEEE*

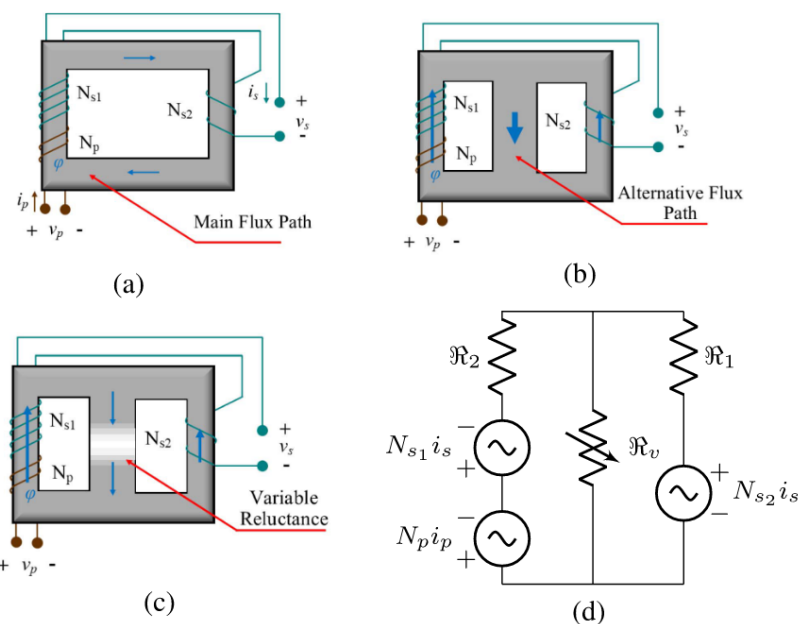
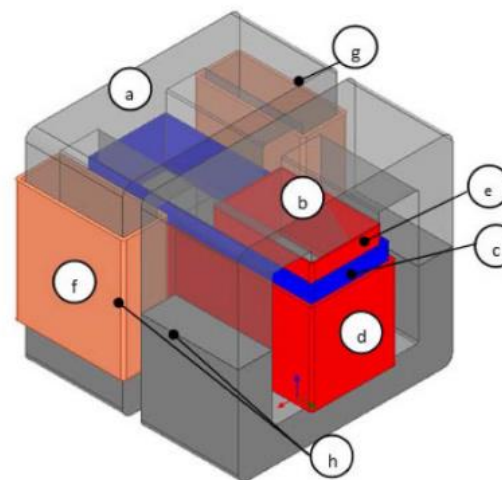
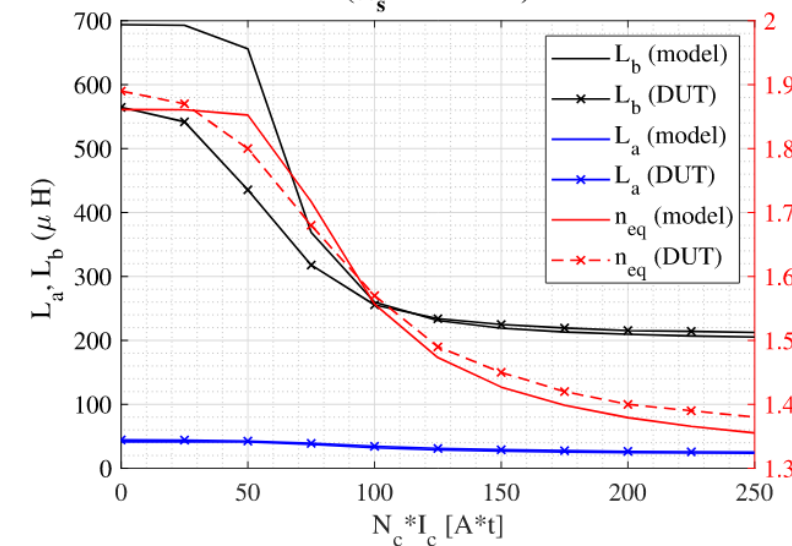


Fig. 1. VT principle of operation. (a) Transformer $N_p : (N_{s1} - N_{s2})$. (b) Transformer $N_p : N_{s1}$. (c) Variable reluctance. (d) Magnetic circuit.

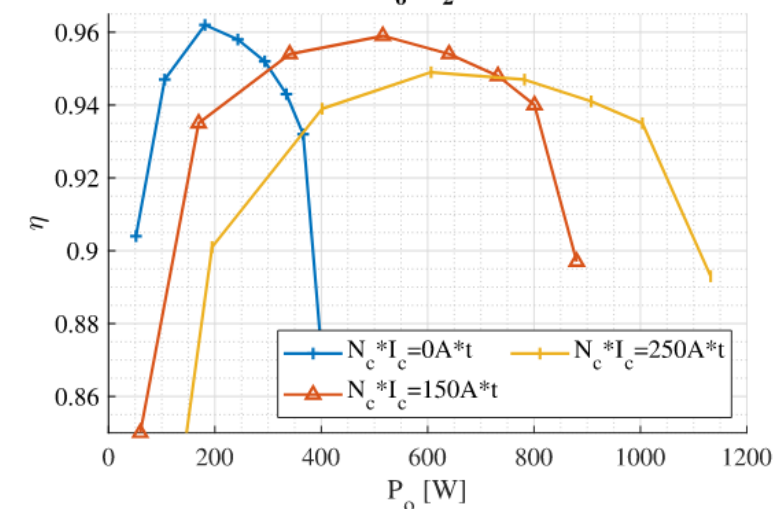


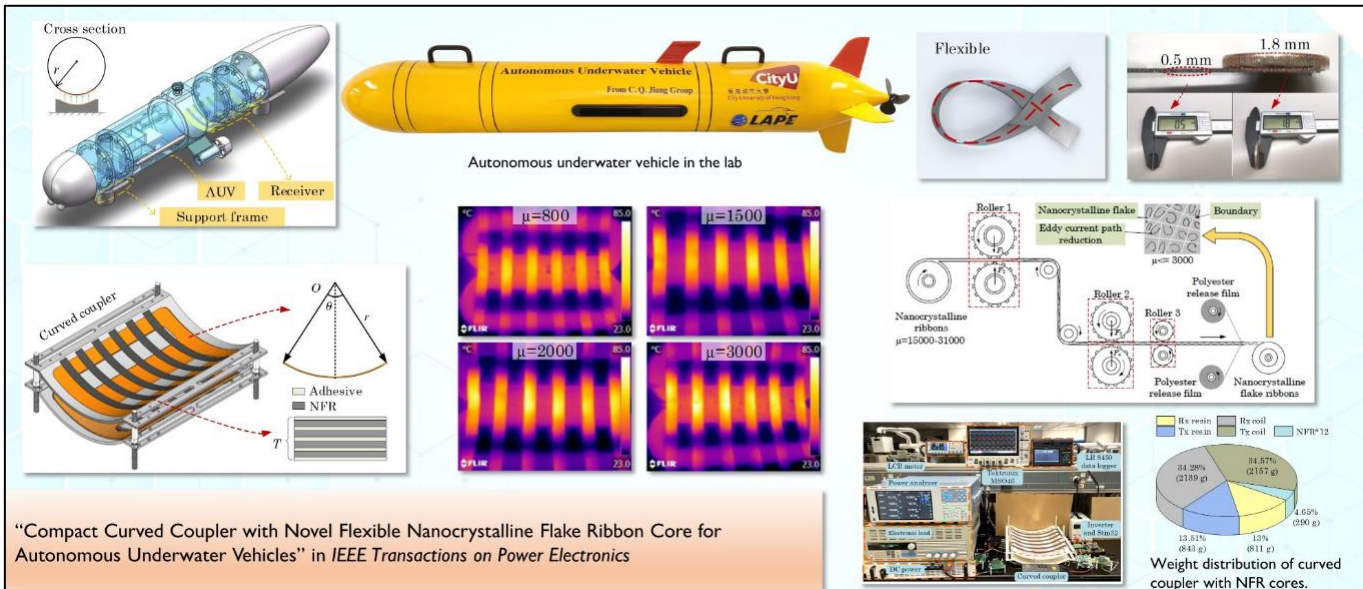
Double E-E core VT structure isometric view.

VT parameters vs Control current (\mathcal{R}_s considered)

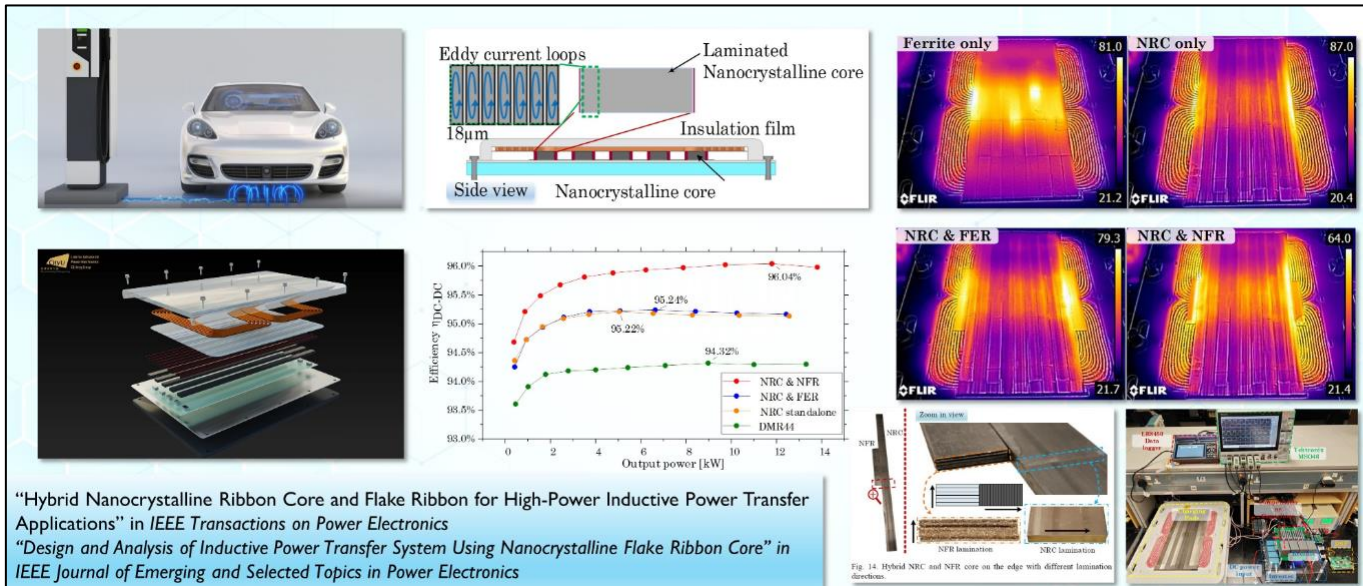
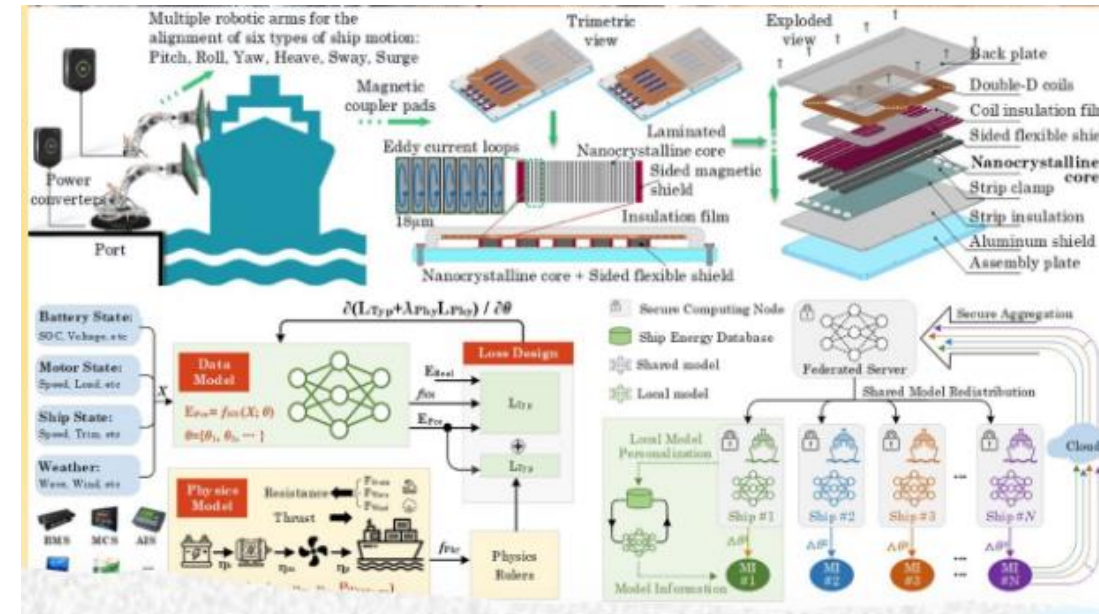


DAB efficiency (control winding losses considered) η vs P_o $V_2=180V$





水下机车的柔性纳米晶片状带芯，IET



高功率无线充电的混合纳米晶代芯分析

**PC: C. Jiang (CityU)**

Power electronics, transport electrification

Trained HKU, Cambridge U

2 book chapters, 60 papers, 15 patents

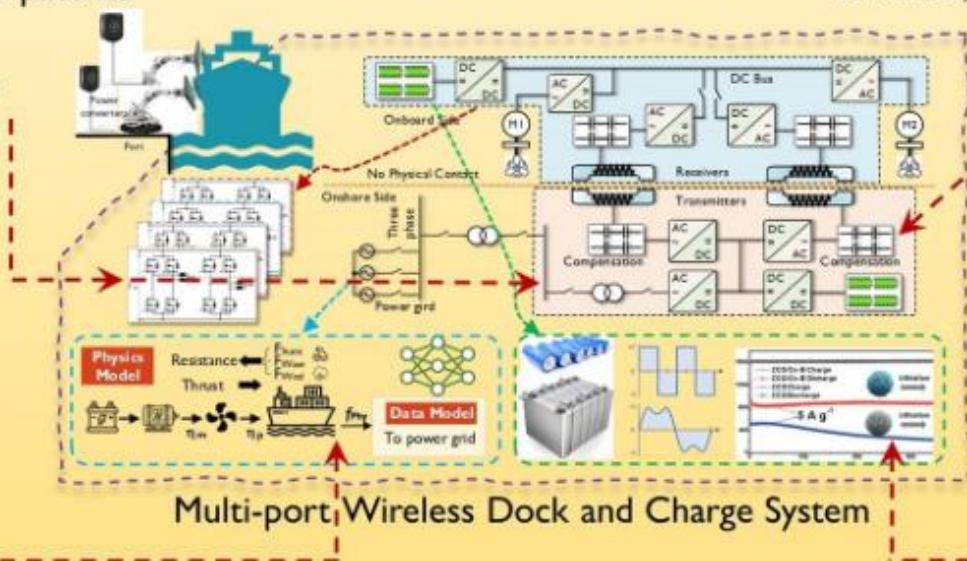
- Winner of Acorn Blue Sky Research, Cambridge University
- Silver Award in Youth Innovation
- Gold Medal in Asia Exhibition

**Co-PI: Y. Wang (HKU)**Energy forecasting,
multi-energy systems

Trained Tsinghua U, ETH Zürich

2 books, 100 papers

- HKU Scholar in Top 1%
- IEEE IAS Ralph Lee Prize Paper Award
- IEEE Trans. on Smart Grid Best Paper (1st)



Multi-port Wireless Dock and Charge System

香港城市大學
City University of Hong Kong
專業 創新 開創全球
Professional-Creative
For The World**Co-PI: C. Tse (CityU)**

Nonlinear circuits and systems, smart grid

Associate Vice-President, Innovation & Enterprise

Director, CityU Academy of Innovation



- IEEE CASS Charles A. Desoer Technical Achievement Award
- Grand Prize & Gold Medal, Silicon Valley International Invention Festival
- Best Paper Awards in IEEE Trans.

Co-PI: X. Yu (PolyU)Electrochemical energy
storage, lithium batteryTrained Tsinghua U,
Japan National Institute

- Best Presentation in Graphene Forum
- Excellent Oral Presentation in Tsinghua



8000V/5500A

双向阻断 IGCT-Plus 器件

关键参数		
$V_{\text{DRM}}/V_{\text{RRM}}$	8000	V
I_{TGQM}	5500	A
I_{TSM}	40	kA
V_{TO}	1.23	V
r_{T}	0.27	mΩ

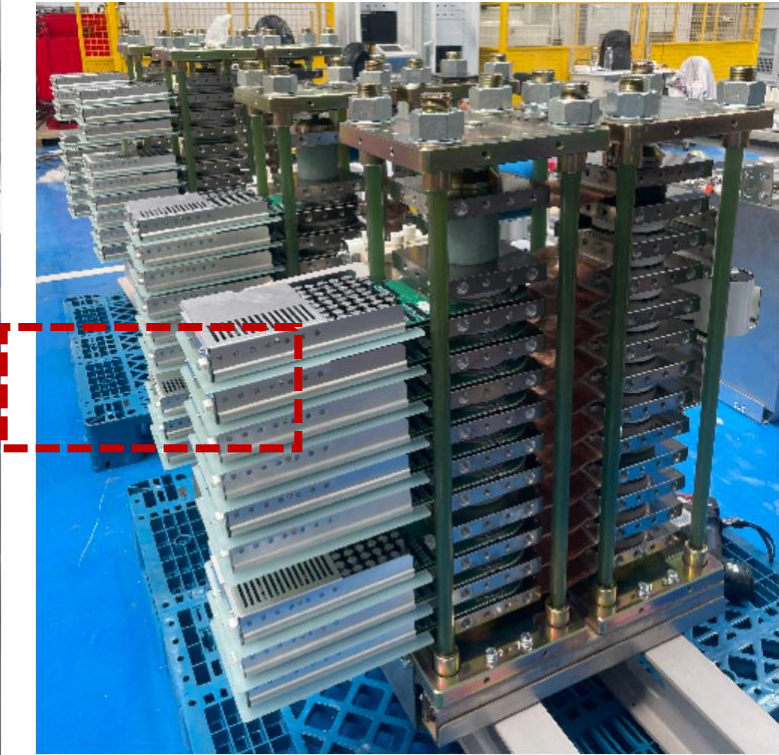
IGCT(集成门极换流晶闸管)

清华大学支直流研究中心：
定制化IGCT器件技术，支流开端技术，功率变换技术，系统分析和控保技术

IGCT技术优势：
大容量，高可靠，高效率，低成本，高密度

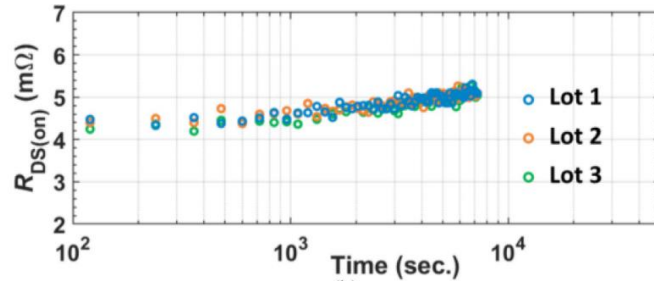
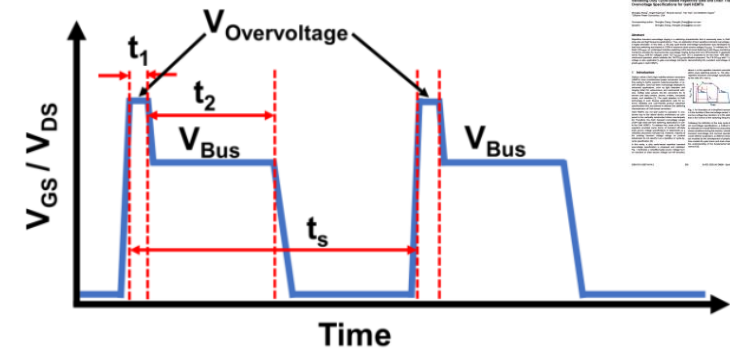


IGCT-MMC阀塔



IGCT-串联ANPC模块

Validating 1% safe operation of overvoltage for GaN HEMTs*



Repetitive transient overvoltage ringing

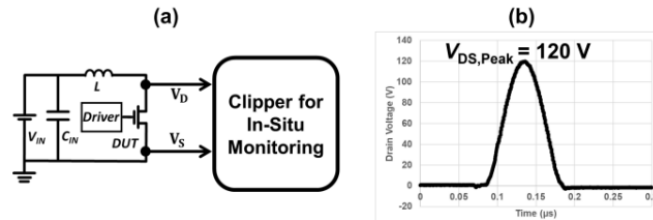


Fig. 4. (a) Schematics of the unclamped inductive switching circuit with *in-situ* $R_{DS(on)}$ monitoring; (b) the measured drain overvoltage waveform with a $V_{DS,Peak}$ of 120 V.

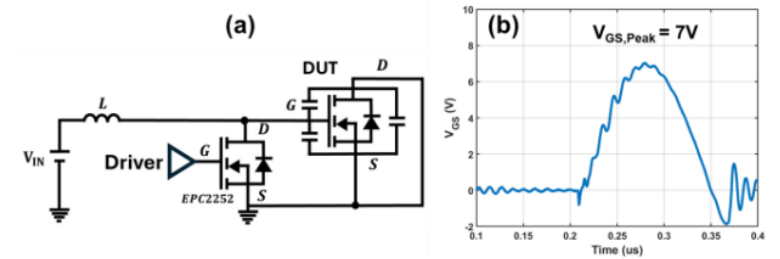


Fig. 8. (a) Schematics of the gate UIS test circuit; (b) the measured gate overvoltage waveform with a $V_{GS,Peak}$ of 7 V.

Fig. 9 and 10 show the excellent overvoltage robustness of the pGaN gate in GaN HEMTs, which also validates the applicability of the 1% duty cycle-based repetitive transient overvoltage specification for the gate.

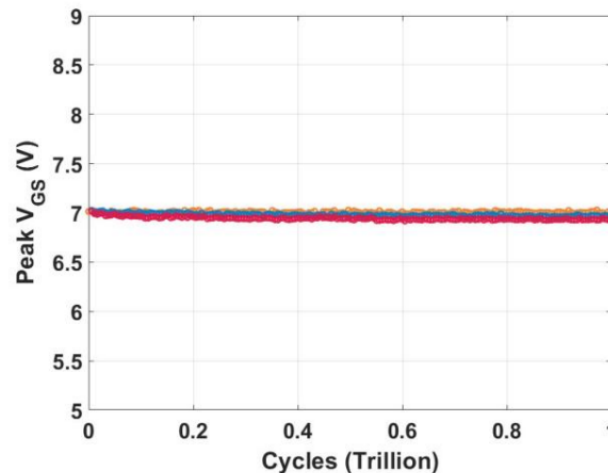


Fig. 9. *In-situ* 7 $V_{DS,Peak}$ monitoring during 1 trillion overvoltage pulses of three EPC2057 GaN transistors, where no measurable $V_{GS,Peak}$ degradation is seen.

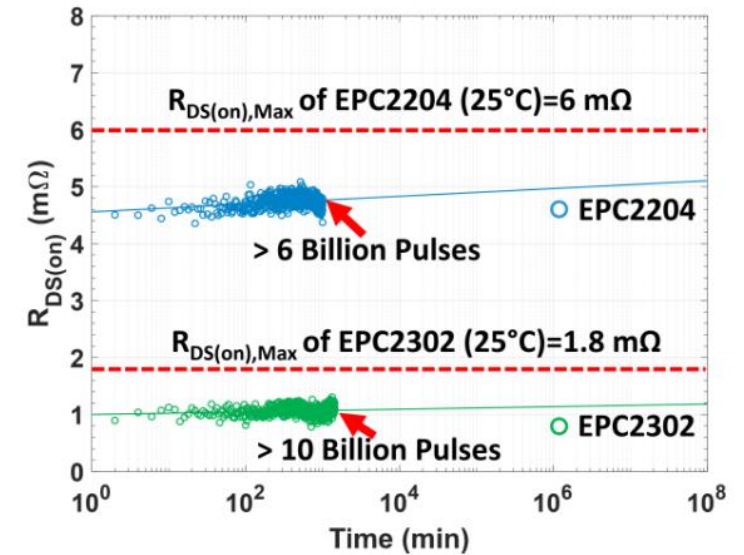


Fig. 6. Evolution of $R_{DS(on)}$ shift of a representative EPC2204 and EPC2302 DUTs under 120 $V_{DS,Peak}$ UIS testing.

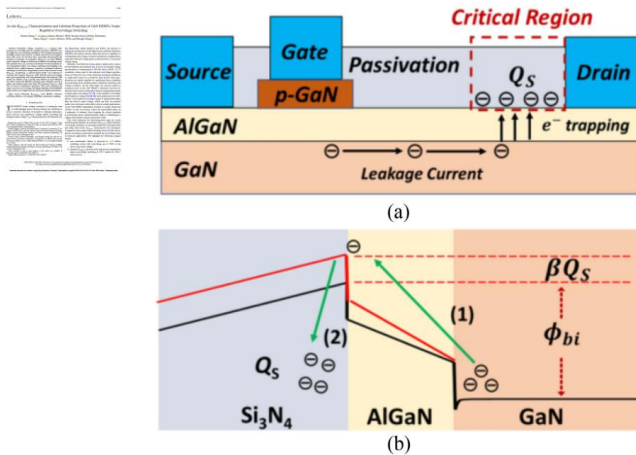


Fig. 5. (a) Illustration of the trapping process in the DUT; the interface electron trapping occurs mainly in the critical high-field region near the drain contact. (b) Illustration of the 1-D trapping model in the vertical direction near the drain. The energy barrier is lifted up when additional electrons get trapped.

IGBT discrete thermal resistance network Tvj

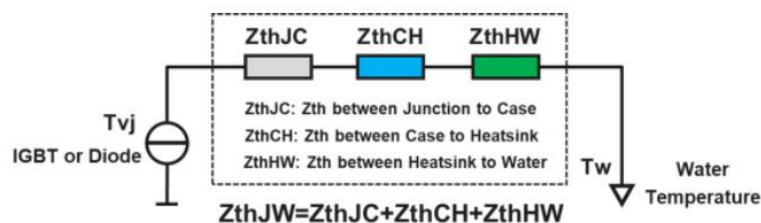


Fig.1 Typical Thermal Network of ZthJW

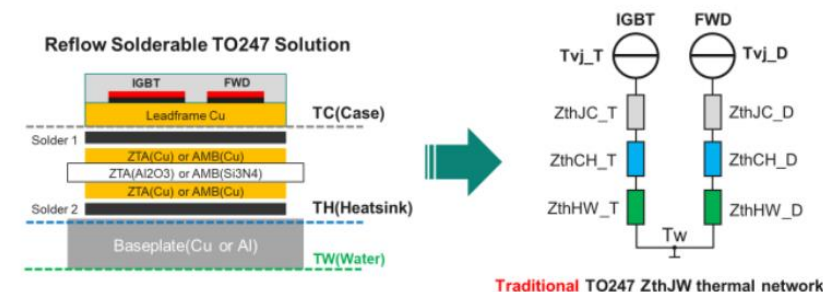


Fig.3. Traditional TO247 ZthJW Thermal Network

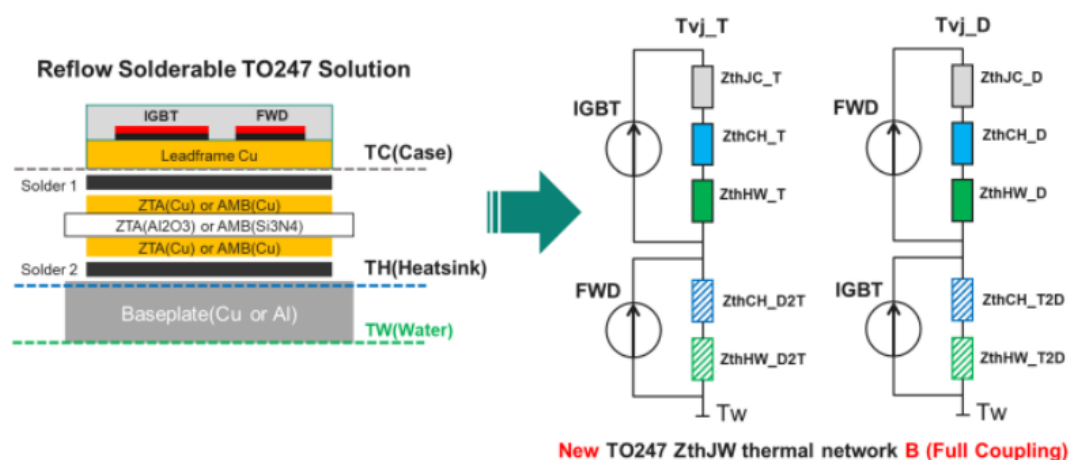


Fig.7. New TO247 ZthJW Thermal Network B (full coupling)

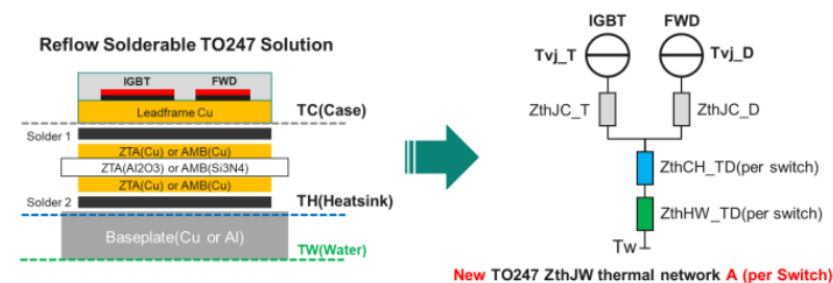
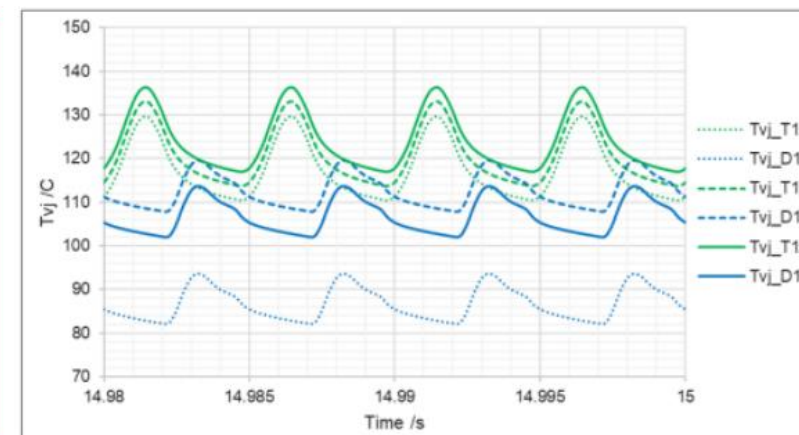


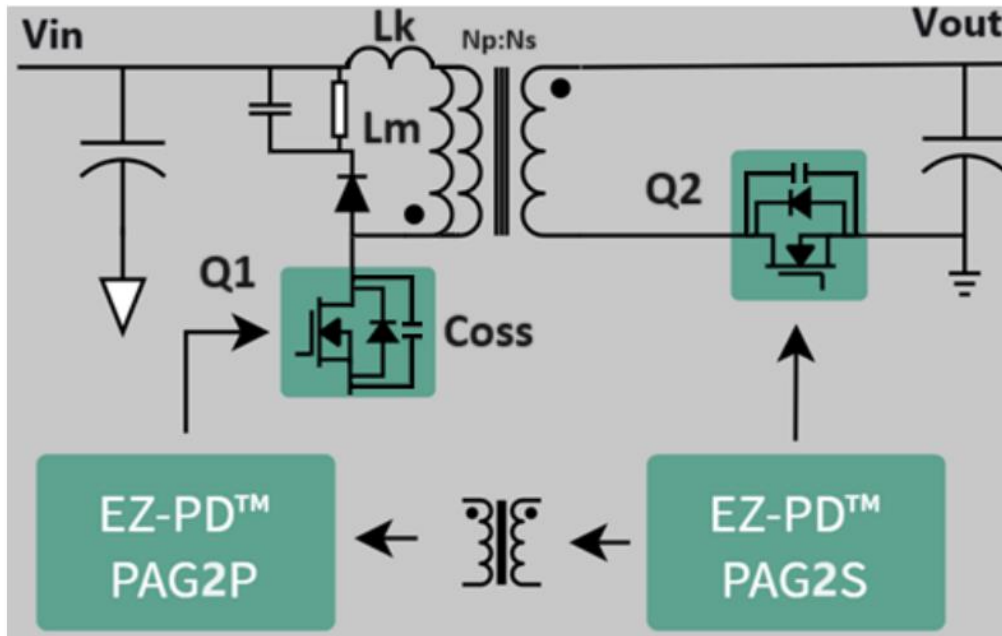
Fig.6. New TO247 ZthJW Thermal Network A (per switch)

比较分析了不同热阻模型的准确度

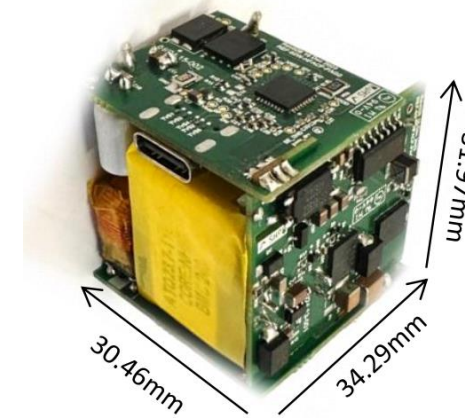
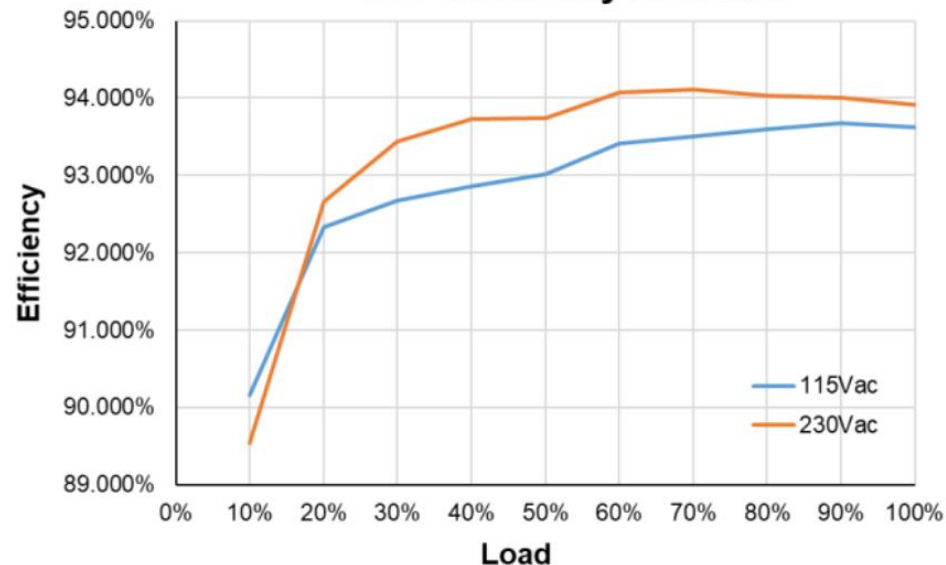
- Condition 1
- ✓ Vdc=480Vdc
- ✓ Fsw=8kHz
- ✓ Fout=200Hz
- ✓ Modi=0.9
- ✓ PF= +0.85
- ✓ Io=160Arms
- ✓ Rg=50hm
- ✓ Tw=65C



High Power Density ZVS Flyback Converter (GaN) *



20V efficiency measure



**USB-PD 66W,
1.89kW/L
Efficiency = 93%**

- AC input voltage: 90~264Vac
- USB PD output:
5V3A, 9V3A, 15V3A, 20V3.25A PDO,
3.3~21V3.25A PPS
- Transformer
Core: ECW23.7F/12.8 DMR96
Inductance Lm: 210uH
Np: 18T 0.1*20
Ns: 3T 0.1*80
Lk: 3uH
- Q1: CoolGaN IGLD60R190D1AUMA1
Vds: 600V
Rdson: 190mΩ
Coss: 32.5pF
Qg: 3.2nC
- Q2: OptiMOS™ 5 BSC050N10NS5
Vds: 100V
Rdson: 5mΩ
Coss: 490pF
Qg: 49nC
- Controller: CYPAP212A1, CYPAS211A1

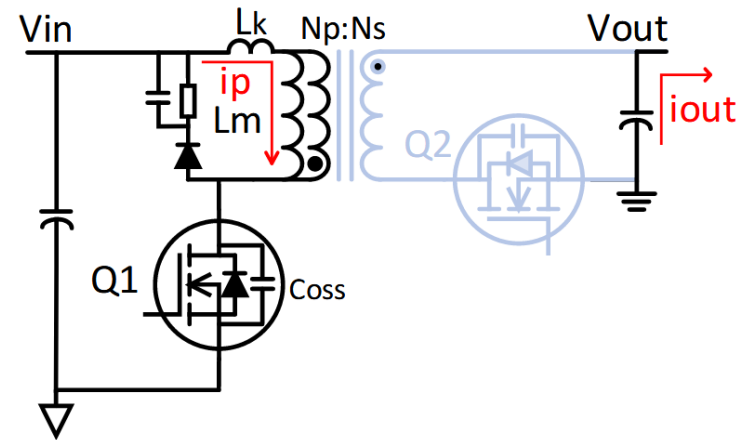


Fig. 3. Equivalent circuit in Primary Energy Storage Stage

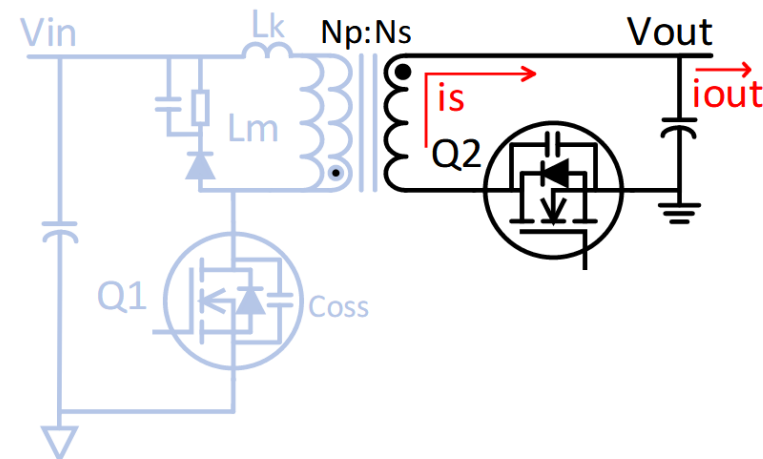
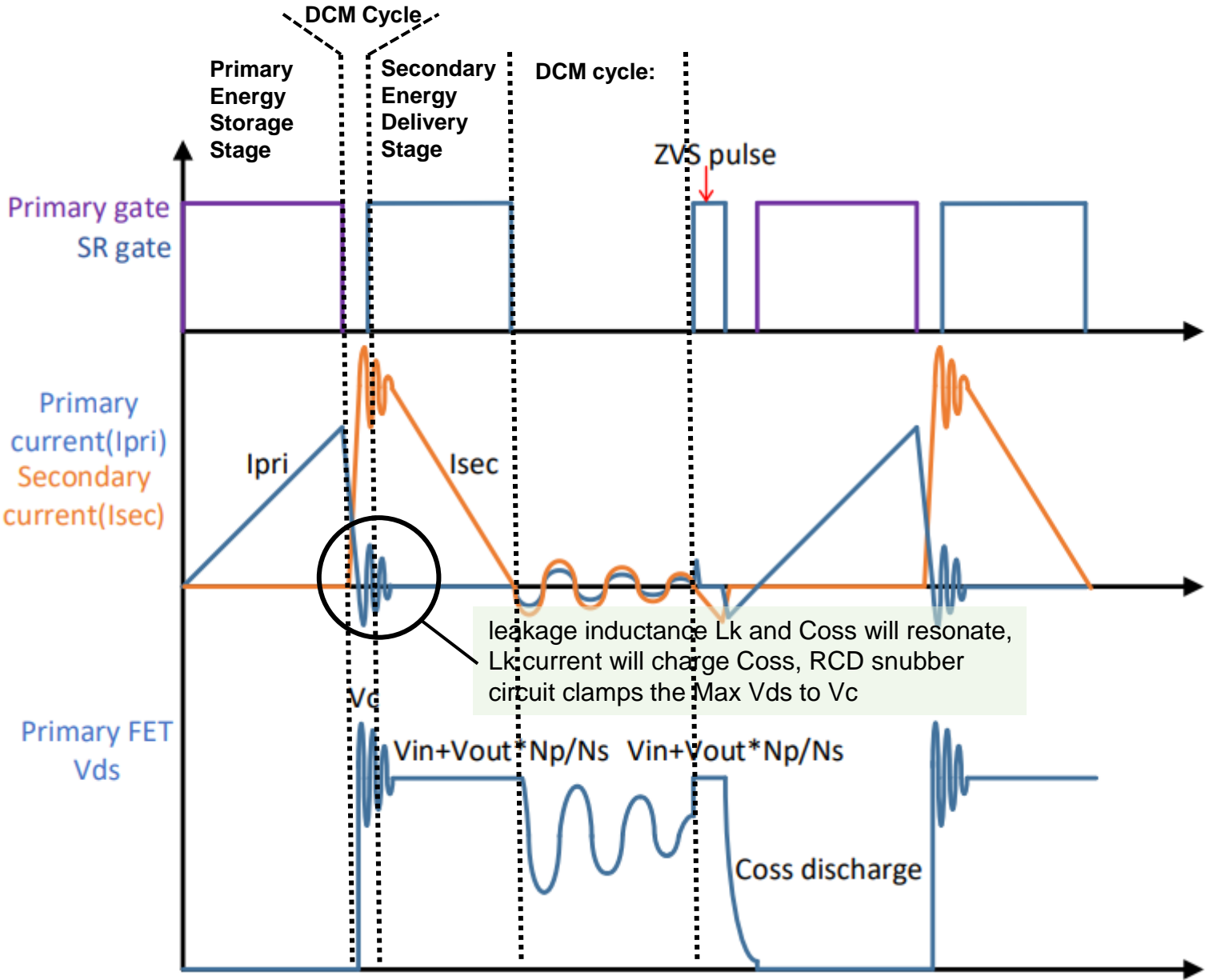


Fig. 5. Equivalent circuit in Secondary Energy Delivery Stage



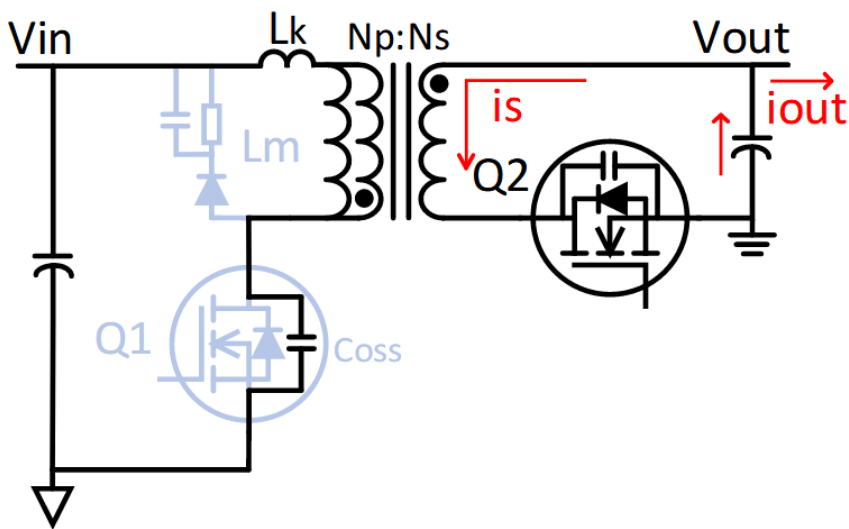


Fig. 8. Equivalent circuit in ZVS pulse

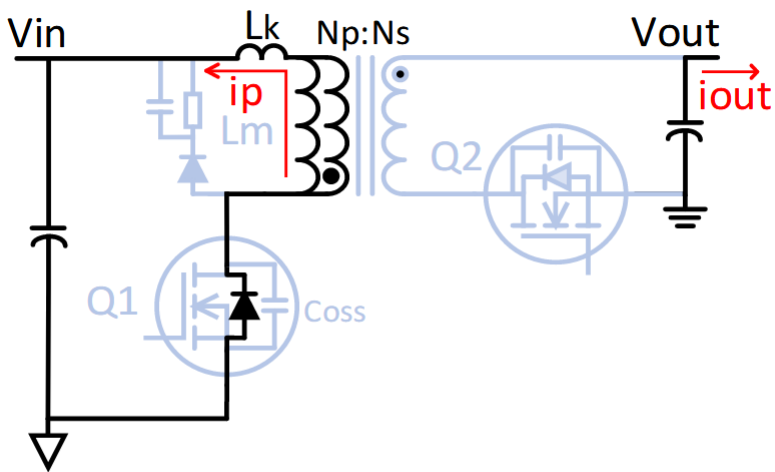


Fig. 10. Equivalent circuit in primary ZVS implementation stage

Zhu 等 - 2024 - High Density USB-PD ZVS Flyback Converter Based on Secondary Side Control.pdf

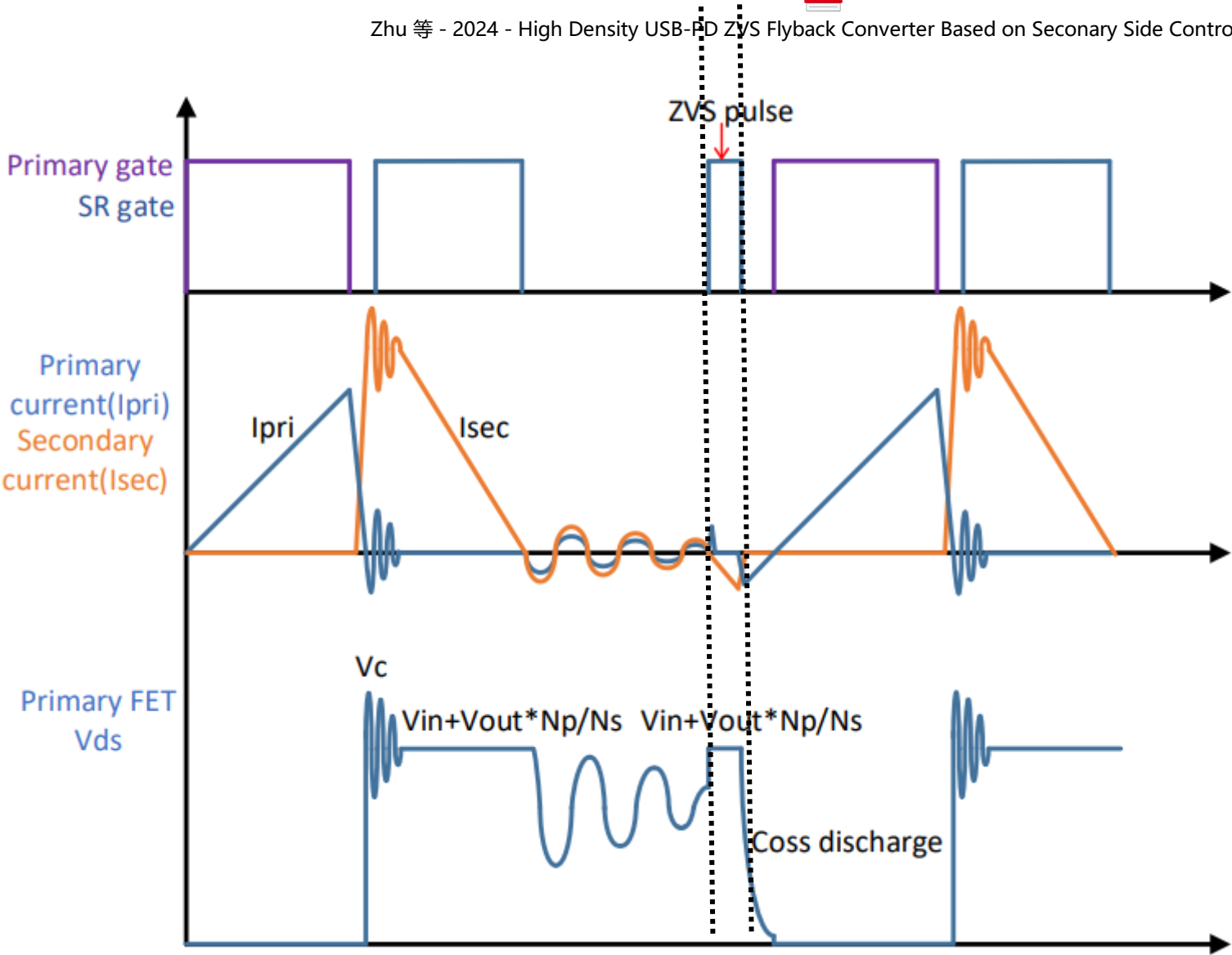




Fig. 1. Cold sprayed hybrid-heat sinks.

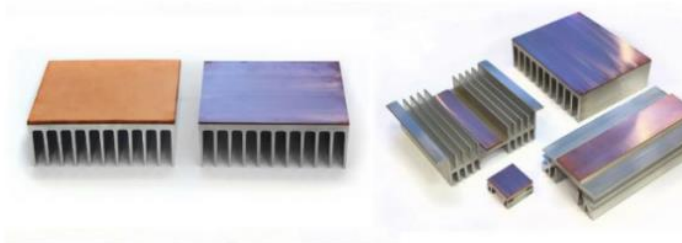


Fig. 2. Cold sprayed hybrid-heat sinks.

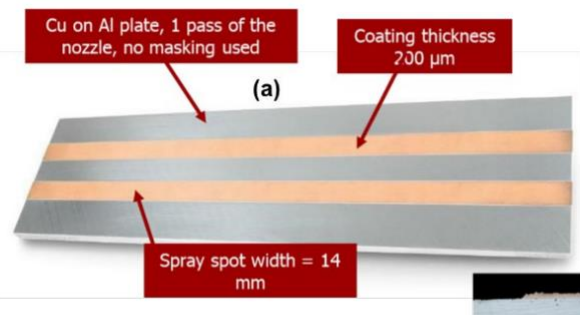
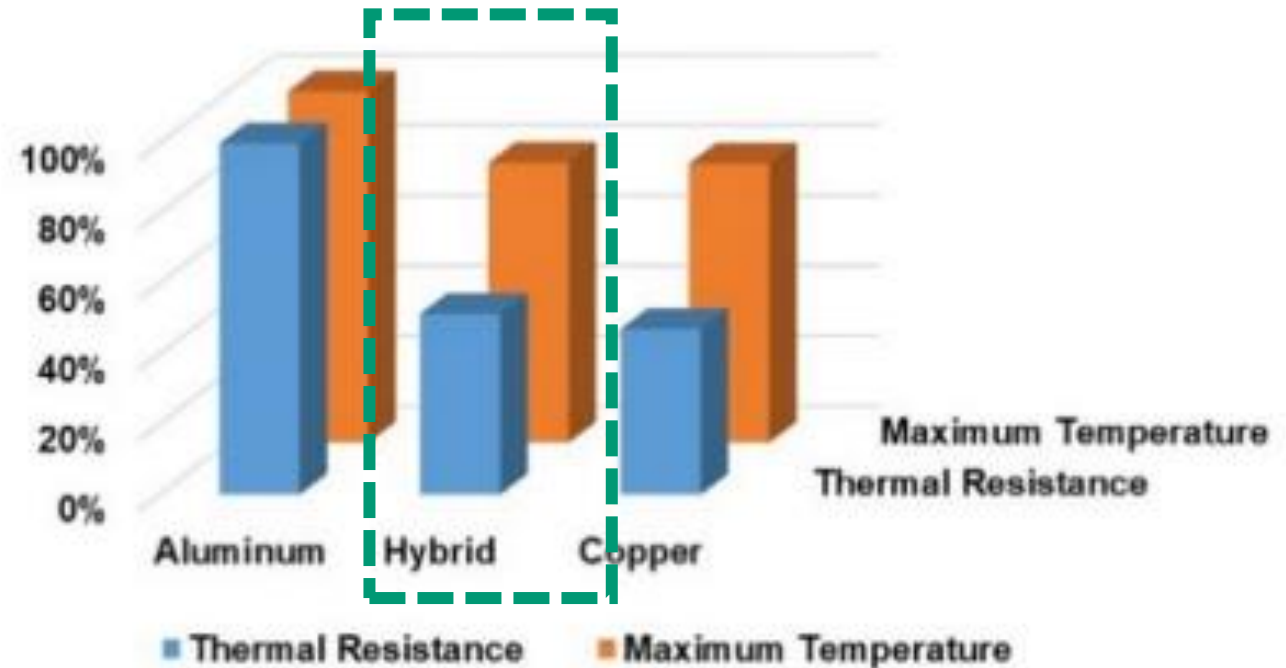


Fig. 2 (a) Cold Spray deposited Cu contact tracks on Aluminum



The results illustrate that the properties of **cold-sprayed Cu** in the as-sprayed state are comparable with bulk-Cu with **98% IACS electrical conductivity** and thermal conductivity of **368 W/mK**. Perfectly gas-tight Cu-deposits with a He-leakage rate smaller than **1×10^{-7} mbar-l/s** have been produced.



Thanks

09/2024

Reference: